

Search Notes

Application/Control No.

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Examiner

Erin M. File

Applicant(s)/Patent under
Reexamination

LAI, YHEAN-SEN

Art Unit

2634

SEARCHED

Class	Subclass	Date	Examiner
375	348	9/12/2005	EMF

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST US PAT, USPGPUB, EPO, JPO DERWENT, IBM (text search only— see search history printout)	9/12/2005	EMF
PALM INVENTORSHIP	4/10/2005	EMF